

Source	Unc. on A_{FB} ($\times 10^{-3}$)	Frac. of total sys. unc. on A_{FB}	Unc. on ΔA_{FB} ($\times 10^{-3}$)	Frac. of total sys. unc. on ΔA_{FB}
PDFs	8.1	47%	0.8	1%
MC and MisID backgrounds stat. unc.	4.1	12%	6.8	42%
$\alpha_S + \mu_F/\mu_R$ scales	3.3	8%	3.2	9%
DY cross section	3.0	7%	0.9	1%
Pileup	2.8	5%	3.8	13%
Fiducial correction	2.7	5%	<0.1	<1%
t̄t cross section	2.7	5%	0.1	<1%
DY p_T correction	2.1	3%	0.8	1%
eμ shape corrections	1.8	2%	0.4	<1%
Integrated luminosity	1.2	1%	1.0	1%
Electron identification/isolation	1.0	1%	2.7	6%
Electron MisID normalization	0.9	1%	4.3	17%
Electron MisID shape	0.8	<1%	2.6	6%
b tagging uncertainty	0.8	<1%	0.3	<1%
p_T^{miss} uncertainties	0.7	<1%	0.5	<1%
Muon identification/isolation	0.6	<1%	1.2	1%
Muon MisID shape	0.5	<1%	0.6	<1%
$\gamma\gamma$ cross section	0.4	<1%	0.6	<1%
Muon MisID normalization	0.4	<1%	0.1	<1%
Electron trigger	0.4	<1%	1.2	1%
Diboson cross section	0.2	<1%	0.1	<1%
Electron reconstruction	0.2	<1%	0.7	<1%
Muon momentum scale	0.1	<1%	0.1	<1%
Electron momentum scale	0.1	<1%	0.1	<1%
Muon trigger	0.1	<1%	0.1	<1%